Search Notes

Application/Control N	lo.
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Applicant(s)/Patent under Reexamination

HAYASE, TAKEO

09/661,916

Examiner

Art Unit

Qamrun Nahar

2191

SEARCHED					
Class	Subclass	Date	Examiner		
717	104, 105	5/16/2005	QN		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
717	104, 105	5/16/2005	QN		
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